
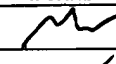

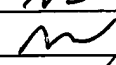
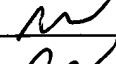
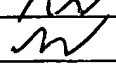
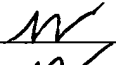
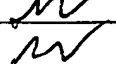

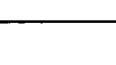
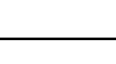
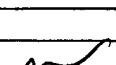
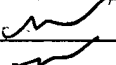
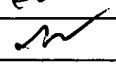
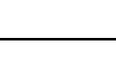


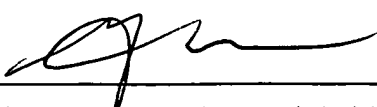
<b>LIST OF REFERENCES CITED BY APPLICANT</b> (Use several sheets if necessary)				<b>ATTY DOCKET NO.</b> 060937-0140-US		<b>APPLICATION NO</b>	
				<b>APPLICANT</b> Wai Mun LEE et al.			
				<b>FILING DATE</b> June 6, 2002		<b>GROUP</b> 1746	



U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	A01	4,617,251	Sizensky				
	A02	5,997,658	Peters et al.				
	A03	6,372,050	Honda et al.				
	A04	6,326,130	Schwartzkopf et al				
	A05	6,276,327	Lee				
	A06	6,320,064	Otring et al.				
	A07	5,417,877	Ward				
	A08	6,261,745	Tanabe et al.				
	A09	5,911,835	Lee				
	A10	5,798,323	Honda et al.				
	A11	6,268,323	Honda et al.				

FOREIGN PATENT DOCUMENTS								
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
						YES	NO	
	B01	1 178 359	EPO					
	B02	2001077063	Japan (Abstract Only)					
	B03	10321569	Japan (Abstract Only)					
	B04							
	B05							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)		
	C01	
	C02	
	C03	

<b>EXAMINER</b> 	<b>DATE CONSIDERED</b> 6/20/05
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>	